

1. Product information

Supplier : JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

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|---------------------------|-----------------|
| Part Number : | CJA03N06 |
| Package Type : | SOT-89-3L |
| Part Description : | 60V SMDs/MOSFET |
| Report Date: | October-25 |

2. Reliability Test Results : PASS

| Test Item | Test condition | Duration | Fail Quantity / S.S |
|---|--|------------------------------|---------------------|
| Pre-and post-stress Electrical test | Ta=25°C | NA | All parts |
| PC Precondition(For SMD Package Only) | JESD22-A113F/J-STD-020 1.Bake:125°C. 2.Soak: 85°C85%RH,168hrs MSL1 or 30°C60%RH,192hrs MSL3 3.Reflow 3Cycles Max 260°C 4.all samples E-Test | >168Hours or >192Hours | 0 / 308 |
| TCT Temperature Cycling Test | JESD22 -A104 -55°C/15min 150°C/15min | 1000cycles | 0 / 77 |
| AC Autoclave | JESD22-A102 121°C, 100%RH | 96Hours | 0 / 77 |
| UHASt Unbiased Highly Accelerated Stress Test | JESD22-A118 130°C, 85%RH | 96Hours | NA |
| THT High Humidity &Temp Test | JESD22-A101 85°C 85%RH | 1000Hours | 0 / 77 |
| HTST High Temperature Storage Test | JESD22 -A103 T=Tstg max | 1000Hours | 0 / 77 |
| H3TRB High Humidity &Temp . Bias Test | JESD22-A101 85°C 85%RH VDS*80% VR<=100V Max | 1000Hours | NA |
| HAST Highly Accelerated Stress Test | JESD22-A110 130°C 85%RH VDS*80% VR≤42V Max | 96Hours | 0 / 77 |
| HTRB High Temperature Revers Bias Test | JESD22 -A108 Tj(max) @VDS *80% | 1000Hours | 0 / 77 |
| HTGB High Temperature Gate Bias Test | JESD22 -A108 Tj(max) VR=BVGS*100% | 1000Hours | 0 / 77 |
| IOL Intermittent Operational Life | MIL-STD-750D Method 1037 △Tj≥100°C On/Off:2min | 15000Cycle | 0 / 77 |
| RSH Resistance to Solder Heat test | JESD22-A111B 260°C±5°C, 10(+2,-0)Seconds | NA | 0 / 30 |
| SD Solderability | J-STD-002 Steam aging:93°C 8hour 2.245°C 3~5s | NA | 0 / 10 |

Notes:

1. Either H3TRB or HAST for reliability test.
2. Either AC or UHASt for reliability test.
3. Detailed MSL of the product refers to the MSL Report.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report